SONY

ICX249A

Diagonal 8mm (Type 1/2) CCD Image Sensor for CCIR Black-and-White Video Cameras

Description

The ICX249AL is an interline CCD solid-state image sensor suitable for CCIR black-and-white video cameras with a diagonal 8mm (Type 1/2) system. smear, D-range, S/N and Sensitivity, characteristics from visible light area to near infrared light area, have been greatly improved compared with the ICX039DLA through the adoption of EXview HAD CCD™ technology.

This chip features a field period readout system and an electronic shutter with variable charge-storage time.

This chip is compatible with and can replace the ICX039DLA.

Features

- · Sensitivity in the near infrared light area (+12dB compared with the ICX039DLA, λ = 945nm)
- High sensitivity (+9dB compared with the ICX039DLA, without IR cut filter)
- Low smear (–15dB compared with the ICX039DLA)
- High D range (+2dB compared with the ICX039DLA)
- High S/N
- High resolution and low dark current
- Excellent antiblooming characteristics
- Continuous variable-speed shutter

Adjustment free (external adjustment also possible with 6 to 14V) Substrate bias:

5Vp-p adjustment free (drive also possible with 0 to 9V) Reset gate pulse:

 Horizontal register: 5V drive

Pin 1

Pin 11

20 pin DIP (Cer-DIP)

Optical black position (Top View)

40

Device Structure

Interline CCD image sensor

Diagonal 8mm (Type 1/2) Image size:

 Number of effective pixels: 752 (H) × 582 (V) approx. 440K pixels Total number of pixels: 795 (H) × 596 (V) approx. 470K pixels

· Chip size: 7.95mm (H) $\times 6.45$ mm (V) · Unit cell size: $8.6\mu m (H) \times 8.3\mu m (V)$

 Optical black: Horizontal (H) direction: Front 3 pixels, rear 40 pixels Vertical (V) direction: Front 12 pixels, rear 2 pixels

• Number of dummy bits: Horizontal 22

Vertical 1 (even fields only)

 Substrate material: Silicon

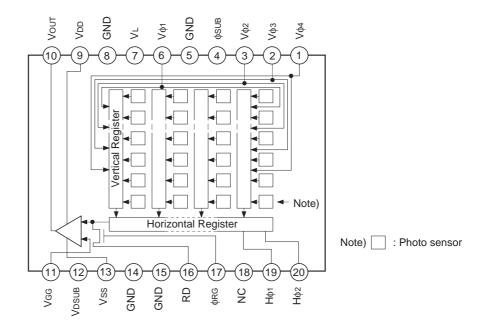
EXview HAD CC

EXview HAD CCD is a trademark of Sony Corporation EXview HAD CCD is a CCD that drastically improves light efficiency by including near infrared light region as a basic structure of HAD (Hole-Accnmulation Diode) sensor.

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Block Diagram and Pin Configuration

(Top View)



Pin Description

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	Vф4	Vertical register transfer clock	11	Vgg	Output circuit gate bias
2	Vфз	Vertical register transfer clock	12	VDSUB	Substrate bias circuit supply voltage
3	Vф2	Vertical register transfer clock	13	Vss	Output circuit source
4	фѕив	Substrate clock	14	GND	GND
5	GND	GND	15	GND	GND
6	Vф1	Vertical register transfer clock	16	RD	Reset drain bias
7	VL	Protective transistor bias	17	фRG	Reset gate clock
8	GND	GND	18	NC	
9	VDD	Output circuit supply voltage	19	Нф1	Horizontal register transfer clock
10	Vouт	Signal output	20	Нф2	Horizontal register transfer clock

Absolute Maximum Ratings

	Item	Ratings	Unit	Remarks
Substrate clock фsub	– GND	-0.3 to +50	V	
Cupply voltage	VDD, VRD, VDSUB, VOUT, VSS – GND	-0.3 to +18	V	
Supply voltage	Vdd, Vrd, Vdsub, Vout, Vss — фsub	-55 to +10	V	
Clask inner valtage	Vφ1, Vφ2, Vφ3, Vφ4 – GND	-15 to +20	V	
Clock input voltage	Vφ1, Vφ2, Vφ3, Vφ4 – φsυв	to +10	V	
Voltage difference be	tween vertical clock input pins	to +15	V	*1
Voltage difference be	tween horizontal clock input pins	to +17	V	
Hφ1, Hφ2 – Vφ4		-17 to +17	V	
φrg, Vgg – GND		-10 to +15	V	
фrg, Vgg — фsuв		-55 to +10	V	
VL — фSUB		-65 to +0.3	V	
Pins other than GND	and φsuв – VL	-0.3 to +30	V	
Storage temperature		-30 to +80	°C	
Operating temperatur	re	-10 to +60	°C	

^{*1 +27}V (Max.) when clock width < 10µs, clock duty factor < 0.1%.

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Bias Conditions 1 [when used in substrate bias internal generation mode]

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output circuit supply voltage	VDD	14.55	15.0	15.45	V	
Reset drain voltage	VRD	14.55	15.0	15.45	V	VRD = VDD
Output circuit gate voltage	Vgg	1.75	2.0	2.25	V	
Output circuit source	Vss	Ground	ed with 390Ω	2 resistor		
Protective transistor bias	VL		*1			
Substrate bias circuit supply voltage V		14.55	15.0	15.45	V	
Substrate clock	фѕив					

^{*1} VL setting is the VvL voltage of the vertical transfer clock waveform, or the same power supply as the VL power supply for the V driver should be used. (When CXD1267AN is used.)

Bias Conditions 2 [when used in substrate bias external adjustment mode]

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output circuit supply voltage	Vdd	14.55	15.0	15.45	V	
Reset drain voltage	VRD	14.55	15.0	15.45	V	VRD = VDD
Output circuit gate voltage	Vgg	1.75	2.0	2.25	V	
Output circuit source	Vss	Ground				
Protective transistor bias	VL		*3			
Substrate bias circuit supply voltage	VDSUB					
Substrate voltage adjustment range	VsuB	6.0 14.0				*5
Substrate voltage adjustment precision	ΔVsuв	-3		+3	%	*5

^{*3} VL setting is the VvL voltage of the vertical transfer clock waveform, or the same power supply as the VL power supply for the V driver should be used. (When CXD1267AN is used.)

VsuB code — one character indication

Code and optimal setting correspond to each other as follows.

VsuB code	Е	f	G	h	J	K	L	m	N	Р	Q	R	S	Т	U	V	W
Optimal setting	6.0	6.5	7.0	7.5	8.0	8.5	9.0	9.5	10.0	10.5	11.0	11.5	12.0	12.5	13.0	13.5	14.0

<Example> "L" \rightarrow Vsub = 9.0V

DC Characteristics

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output circuit supply current	IDD		5.0	10.0	mA	

^{*2} Do not apply a DC bias to the substrate clock pin, because a DC bias is generated within the CCD.

^{*4} Connect to GND or leave open.

^{*5} The setting value of the substrate voltage (Vsub) is indicated on the back of the image sensor by a special code. When adjusting the substrate voltage externally, adjust the substrate voltage to the indicated voltage. The adjustment precision is ±3%. However, this setting value has not significance when used in substrate bias internal generation mode.

Clock Voltage Conditions

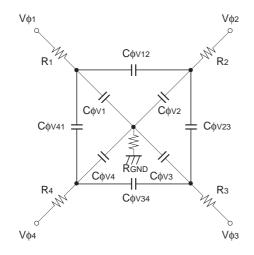
Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Readout clock voltage	Vvт	14.55	15.0	15.45	V	1	
	Vvh1, Vvh2	-0.05	0	0.05	V	2	VvH = (VvH1 + VvH2)/2
	VvH3, VvH4	-0.2	0	0.05	V	2	
	VVL1, VVL2, VVL3, VVL4	-9.6	-9.0	-8.5	٧	2	Vvl = (Vvl3 + Vvl4)/2
	Vφv	8.3	9.0	9.65	Vp-p	2	$V\phi V = VVHN - VVLN (n = 1 \text{ to } 4)$
Vertical transfer clock	Vvh1 — Vvh2			0.1	V	2	
voltage	VvH3 — VvH	-0.25		0.1	٧	2	
	VvH4 — VvH	-0.25		0.1	V	2	
	Vvнн			0.5	٧	2	High-level coupling
	VVHL			0.5	٧	2	High-level coupling
	Vvlh			0.5	٧	2	Low-level coupling
	VVLL			0.5	V	2	Low-level coupling
Horizontal transfer	Vфн	4.75	5.0	5.25	Vp-p	3	
clock voltage	VHL	-0.05	0	0.05	V	3	
	VRGL		*1	•	٧	4	
Reset gate clock voltage*1	V¢RG	4.5	5.0	5.5	Vp-р	4	
	Vrglh – Vrgll			0.8	V	4	Low-level coupling
Substrate clock voltage	Vфsuв	23.0	24.0	25.0	Vp-р	5	

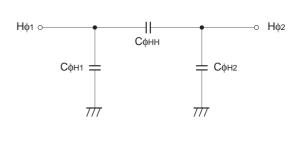
^{*1} Input the reset gate clock without applying a DC bias. In addition, the reset gate clock can also be driven with the following specifications.

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Reset gate clock	Vrgl	-0.2	0	0.2	V	4	
voltage	Vørg	8.5	9.0	9.5	Vp-p	4	

Clock Equivalent Circuit Constant

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Capacitance between vertical transfer clock	Сф∨1, Сф∨3		1800		pF	
and GND	Сф∨2, Сф∨4		2200		pF	
Capacitance between vertical transfer clocks	СфV12, СфV34		450		pF	
Capacitance between vertical transfer clocks	Сф∨23, Сф∨41		270		pF	
Capacitance between horizontal transfer clock	Сфн1		64		pF	
and GND	Сфн2		62		pF	
Capacitance between horizontal transfer clocks	Сфнн		47		pF	
Capacitance between reset gate clock and GND	Сфяс		8		pF	
Capacitance between substrate clock and GND	Сфѕив		400		pF	
Vertical transfer clock series resistor	R1, R2, R3, R4		68		Ω	
Vertical transfer clock ground resistor	RGND		15		Ω	



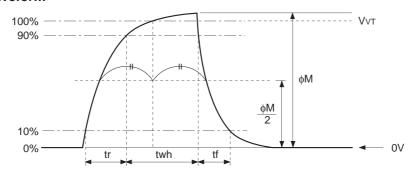


Vertical transfer clock equivalent circuit

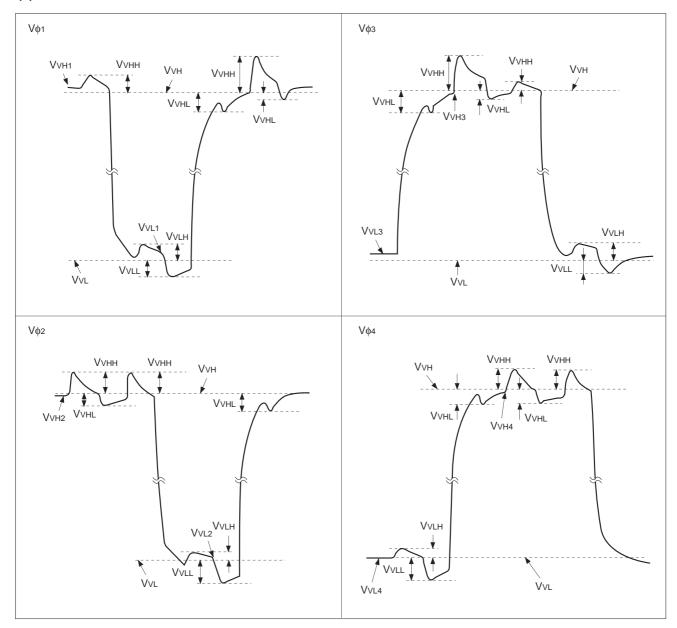
Horizontal transfer clock equivalent circuit

Drive Clock Waveform Conditions

(1) Readout clock waveform



(2) Vertical transfer clock waveform

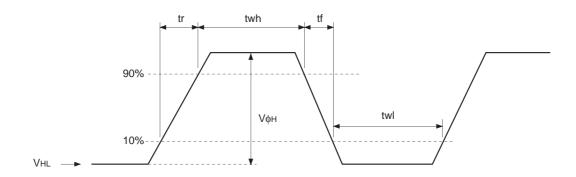


 $V_{VH} = (V_{VH1} + V_{VH2})/2$

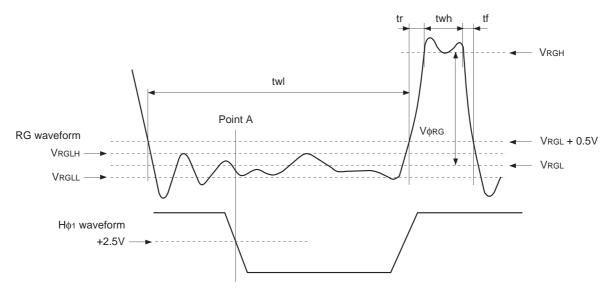
 $V \lor L = (V \lor L3 + V \lor L4)/2$

 $V\phi \lor = V\lor Hn - V\lor Ln (n = 1 to 4)$

(3) Horizontal transfer clock waveform



(4) Reset gate clock waveform



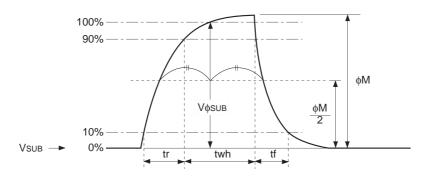
 V_{RGLH} is the maximum value and V_{RGLL} is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG. In addition, V_{RGL} is the average value of V_{RGLH} and V_{RGLL} .

 $V_{RGL} = (V_{RGLH} + V_{RGLL})/2$

Assuming VRGH is the minimum value during the interval twh, then:

 $V\phi RG = VRGH - VRGL$

(5) Substrate clock waveform



Clock Switching Characteristics

	ltom	Cumbal		twh			twl			tr			tf		Unit	Domorko
	Item	Symbol	Min.	Тур.	Мах.	Uniii	Remarks									
Re	adout clock	VT	2.3	2.5					0.5			0.5			μs	During readout
Ve	rtical transfer ck	Vφ1, Vφ2, Vφ3, Vφ4										15		250	ns	*1
Horizontal transfer clock	During imaging	Нф		20			20			15	19		15	19	ns	*2
oriza Isfer	During parallel-	Нф1		5.38						0.01			0.01		μs	
ta H	serial conversion	Нф2					5.38			0.01			0.01		μυ	
Re	set gate clock	фRG	11	13			51			3			3		ns	
Sul	bstrate clock	фѕив	1.5	1.8							0.5			0.5	μs	During drain charge

^{*1} When vertical transfer clock driver CXD1267AN is used.

^{*2} $tf \ge tr - 2ns$.

Item	Symbol		two		Unit	Remarks	
item	Symbol	Min.	Тур.	Max.	Offic	Remarks	
Horizontal transfer clock	Н ф1, Н ф2	16	20		ns	*3	

^{*3} The overlap period for twh and twl of horizontal transfer clocks $H\phi_1$ and $H\phi_2$ is two.

Image Sensor Characteristics

 $(Ta = 25^{\circ}C)$

Item	Symbol	Min.	Тур.	Max.	Unit	Measurement method	Remarks
Sensitivity	S	4500	5500		mV	1	*1
Saturation signal	Vsat	900			mV	2	Ta = 60°C
Smear	Sm		0.00005	0.00018	%	3	
Video signal shading	SH			20	%	4	Zone 0 and I
Video signal snading	311			25	%	4	Zone 0 to II'
Dark signal	Vdt			2	mV	5	Ta = 60°C
Dark signal shading	ΔVdt			1	mV	6	Ta = 60°C
Flicker	F			2	%	7	
Lag	Lag			0.5	%	8	

^{*1} Sensitivity data is the conversion value by Measurement method 1.

Zone Definition of Video Signal Shading

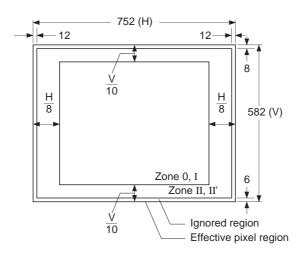


Image Sensor Characteristics Measurement Method

Measurement conditions

1) In the following measurements, the device drive conditions are at the typical values of the bias and clock voltage conditions. (When used with substrate bias external adjustment, set the substrate voltage to the value indicated on the device and connect VDSUB pin to GND or leare it open.)

2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black (OB) level is used as the reference for the signal output, and the value measured at point [*A] in the drive circuit example is used.

Definition of standard imaging conditions

1) Standard imaging condition I:

Use a pattern box (luminance: 706cd/m², color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens and image at F8. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity. (IR cut filter is not applicable.)

2) Standard imaging condition II:

Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens and the luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm. (IR cut filter is not applicable.)

Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/500s, measure the signal output (Vs) at the center of the screen and substitute the value into the following formula.

$$S = Vs \times \frac{500}{50} [mV]$$

Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with the average value of the signal output, 200mV, measure the minimum value of the signal output.

3. Smear

Set to standard imaging condition II. Adjust the luminous intensity to 500 times the intensity with the average value of the signal output, 200mV. When the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value (VSm [mV]) of the signal output and substitute the value into the following formula.

$$Sm = \frac{VSm}{200} \times \frac{1}{500} \times \frac{1}{10} \times 100 \text{ [\%] (1/10V method conversion value)}$$

4. Video signal shading

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the signal output is 200mV. Then measure the maximum (Vmax [mV]) and minimum (Vmin [mV]) values of the signal output and substitute the values into the following formula.

$$SH = (Vmax - Vmin)/200 \times 100 [\%]$$

5. Dark signal

Measure the average value of the signal output (Vdt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

6. Dark signal shading

After measuring 5, measure the maximum (Vdmax [mV]) and minimum (Vdmin [mV]) values of the dark signal output and substitute the values into the following formula.

$$\Delta Vdt = Vdmax - Vdmin [mV]$$

7. Flicker

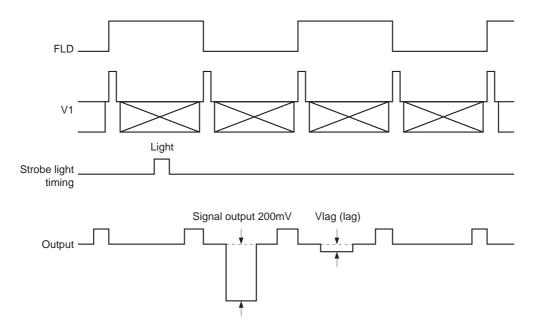
Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the signal output is 200mV, and then measure the difference in the signal level between fields (Δ Vf [mV]). Then substitute the value into the following formula.

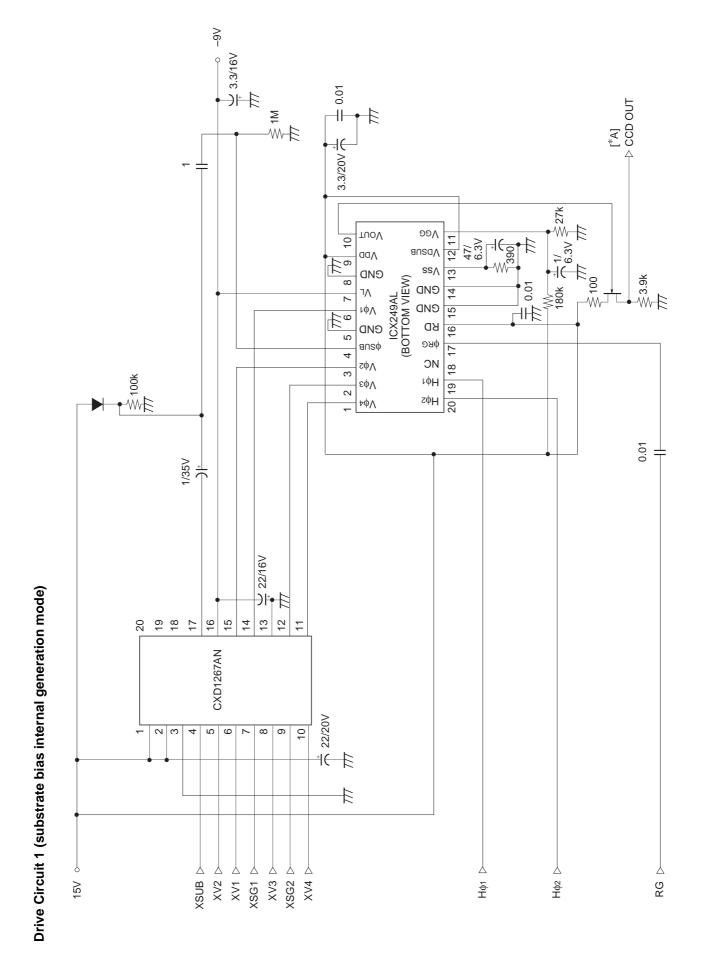
$$F = (\Delta Vf/200) \times 100 [\%]$$

8. Lag

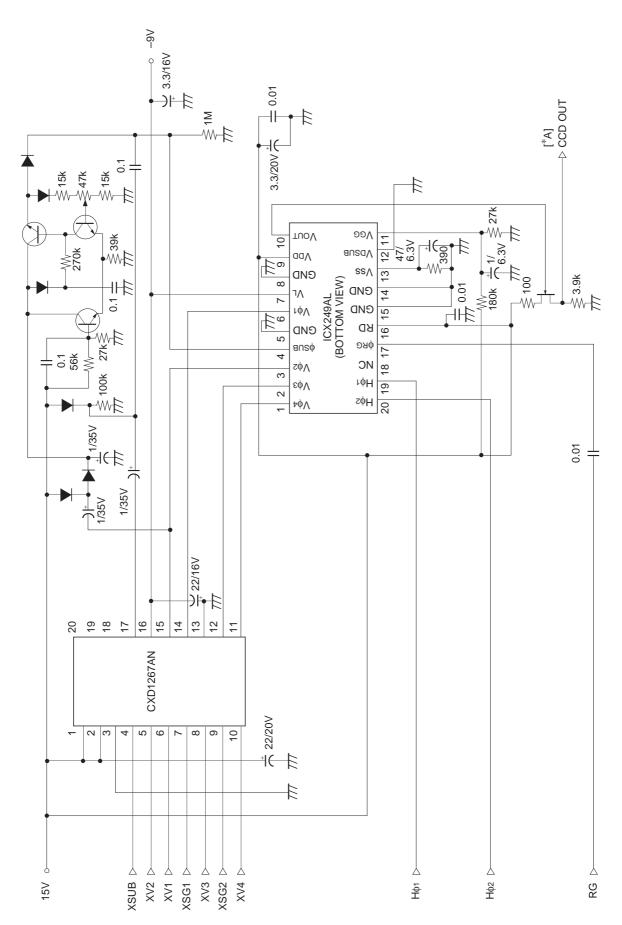
Adjust the signal output value generated by strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Vlag). Substitute the value into the following formula.

$$Lag = (Vlag/200) \times 100 [\%]$$

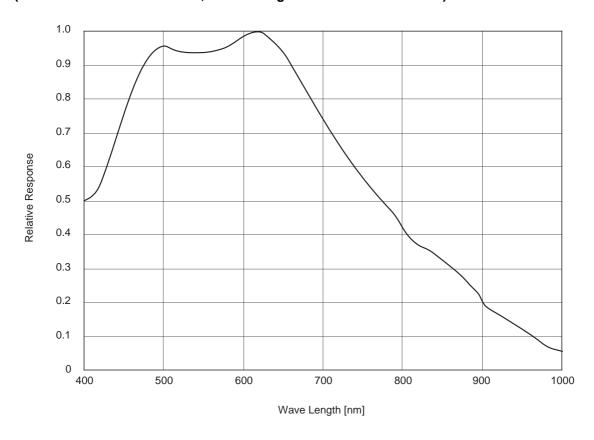




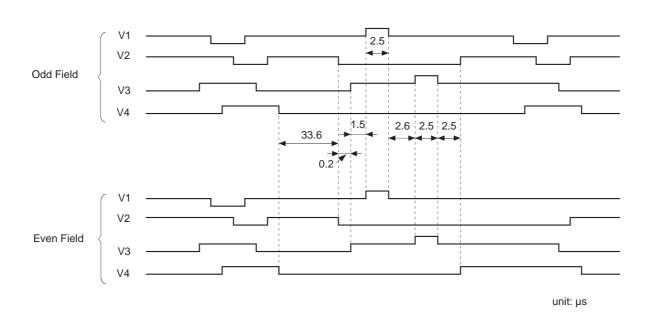


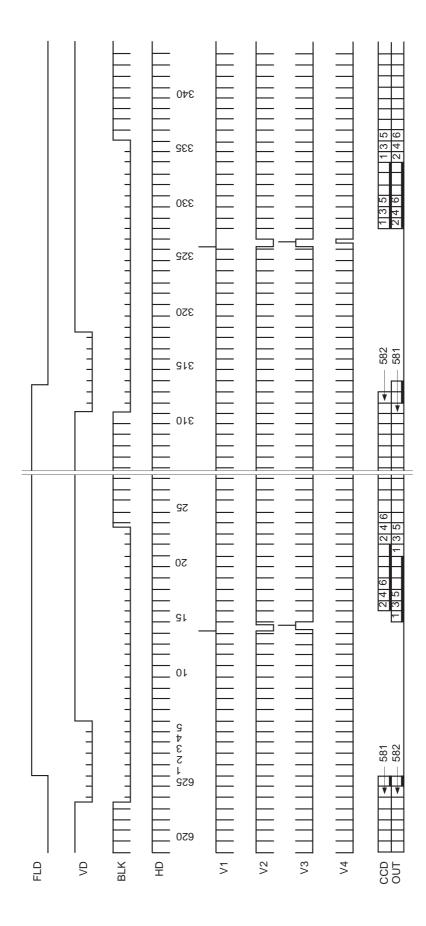


Spectral Sensitivity Characteristics (Includes lens characteristics, excludes light source characteristics)

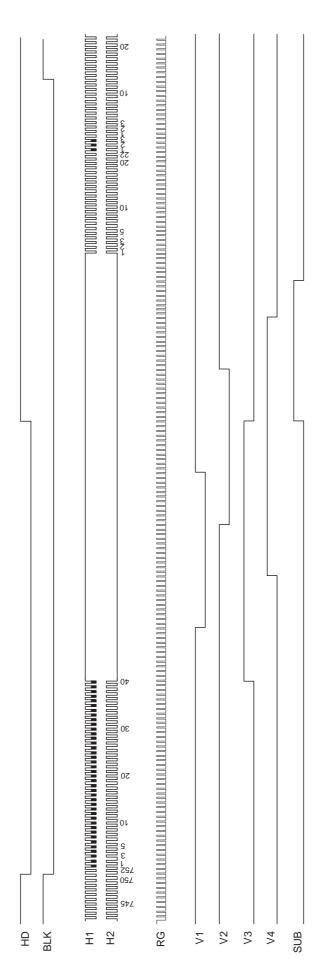


Sensor Readout Clock Timing Chart









SONY ICX249AL

Notes on Handling

1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.

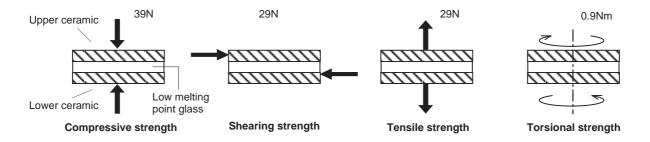
3) Dust and dirt protection

Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operation as required, and use them.

- a) Perform all assembly operations in a clean room (class 1000 or less).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.

4) Installing (attaching)

a) Remain within the following limits when applying a static load to the package. Do not apply any load more than 0.7mm inside the outer perimeter of the glass portion, and do not apply any load or impact to limited portions. (This may cause cracks in the package.)



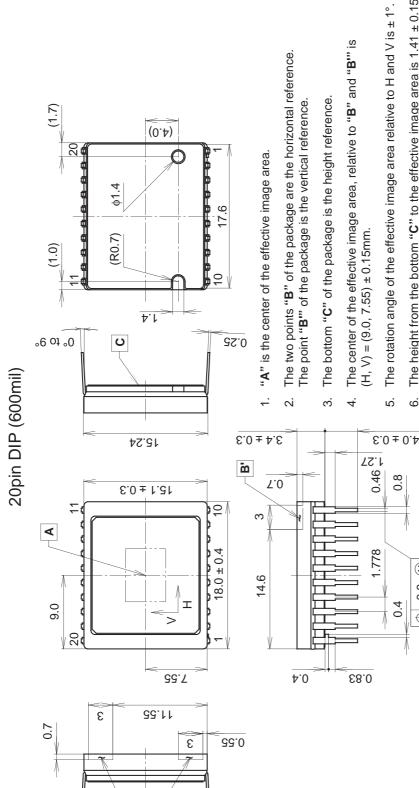
b) If a load is applied to the entire surface by a hard component, bending stress may be generated and the package may fracture, etc., depending on the flatness of the ceramic portions. Therefore, for installation, use either an elastic load, such as a spring plate, or an adhesive.

- c) The adhesive may cause the marking on the rear surface to disappear, especially in case the regulated voltage value is indicated on the rear surface. Therefore, the adhesive should not be applied to this area, and indicated values should be transferred to other locations as a precaution.
- d) The upper and lower ceramic are joined by low melting point glass. Therefore, care should be taken not to perform the following actions as this may cause cracks.
 - Applying repeated bending stress to the outer leads.
 - Heating the outer leads for an extended period with a soldering iron.
 - Rapidly cooling or heating the package.
 - Applying any load or impact to a limited portion of the low melting point glass using tweezers or other sharp tools.
- Prying at the upper or lower ceramic using the low melting point glass as a fulcrum.
 Note that the same cautions also apply when removing soldered products from boards.
- e) Acrylate anaerobic adhesives are generally used to attach CCD image sensors. In addition, cyanoacrylate instantaneous adhesives are sometimes used jointly with acrylate anaerobic adhesives. (reference)

5) Others

- a) Do not expose to strong light (sun rays) for long periods. For continuous using under cruel condition exceeding the normal using condition, consult our company.
- b) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- c) This CCD image sensor has sensitivity in the near infrared area. Its focus may not match in the same condition under visible light /near infrared light because of aberration.

Unit: mm Package Outline



The center of the effective image area, relative to "B" and "B" is (H, V) = (9.0, 7.55) $\pm\,0.15$ mm.

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The tilt of the effective image area relative to the bottom "C" is less than 60µm. 7

The thickness of the cover glass is 0.75mm, and the refractive index is 1.5. ω.

om must not be used for reference of fixin		

TIN PLATING

Cer-DIP

PACKAGE MATERIAL

LEAD TREATMENT

PACKAGE STRUCTURE

42 ALLOY

2.6g

PACKAGE WEIGHT

LEAD MATERIAL